# 2SB0942 (2SB942), 2SB0942A (2SB942A)

### Silicon PNP epitaxial planar type

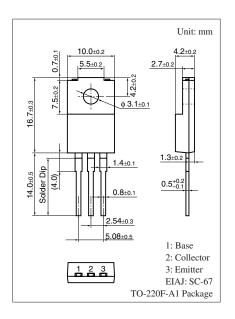
For low-frequency power amplification Complementary to 2SD1267, 2SD1267A

#### ■ Features

- $\bullet$  High forward current transfer ratio  $h_{F\!E}$  which has satisfactory linearity
- Large collector-emitter saturation voltage V<sub>CE(sat)</sub>
- Full-pack package which can be installed to the heat sink with one screw

#### ■ Absolute Maximum Ratings $T_C = 25$ °C

Parameter	Symbol	Rating	Unit	
Collector-base voltage	2SB0942	$V_{CBO}$	-60	V
(Emitter open)	2SB0942A		-80	
Collector-emitter voltage	2SB0942	V <sub>CEO</sub>	-60	V
(Base open)	2SB0942A		-80	
Emitter-base voltage (Col	$V_{EBO}$	-5	V	
Collector current	$I_C$	-4	A	
Peak collector current	$I_{CP}$	-8	A	
Collector power	P <sub>C</sub>	40	W	
dissipation	$T_a = 25^{\circ}C$		2	
Junction temperature	$T_{j}$	150	°C	
Storage temperature	$T_{stg}$	-55 to +150	°C	



### $\blacksquare$ Electrical Characteristics $\,T_{C}=25^{\circ}C\pm3^{\circ}C$

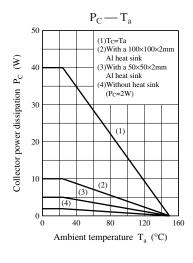
Parameter		Symbol	Conditions	Min	Тур	Max	Unit
Collector-emitter voltage	2SB0942	V <sub>CEO</sub>	$I_C = -30 \text{ mA}, I_B = 0$	-60			V
(Base open)	2SB0942A			-80			
Base-emitter voltage		$V_{BE}$	$V_{CE} = -4 \text{ V}, I_{C} = -3 \text{ A}$			-2	V
Collector-emitter	2SB0942	I <sub>CES</sub>	$V_{CE} = -60 \text{ V}, V_{BE} = 0$			-400	μΑ
cutoff current (E-B short)	2SB0942A		$V_{CE} = -80 \text{ V}, V_{BE} = 0$			-400	
Collector-emitter cutoff current (Base open)		$I_{CEO}$	$V_{CE} = -30 \text{ V}, I_B = 0$			-700	μΑ
Emitter-base cutoff current (Collector open)		$I_{EBO}$	$V_{EB} = -5 \text{ V}, I_C = 0$			-1	mA
Forward current transfer ratio		h <sub>FE1</sub> *	$V_{CE} = -4 \text{ V}, I_{C} = -1 \text{ A}$	40		250	_
		h <sub>FE2</sub>	$V_{CE} = -4 \text{ V}, I_{C} = -3 \text{ A}$	15			
Collector-emitter saturation	voltage	V <sub>CE(sat)</sub>	$I_C = -4 \text{ A}, I_B = -0.4 \text{ A}$			-1.5	V
Transition frequency		$f_T$	$V_{CE} = -10 \text{ V}, I_{C} = -0.1 \text{ A}, f = 10 \text{ MHz}$		30		MHz
Turn-on time		t <sub>on</sub>	$I_C = -4 A$ , $I_{B1} = -0.4 A$ , $I_{B2} = 0.4 A$		0.2		μs
Storage time		t <sub>stg</sub>	$V_{CC} = -50 \text{ V}$		0.5		μs
Fall time		$t_{\mathrm{f}}$			0.2		μs

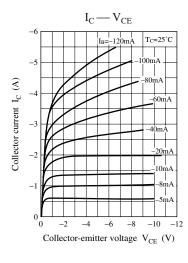
Note) 1. Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors.

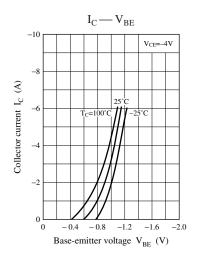
#### 2. \*: Rank classification

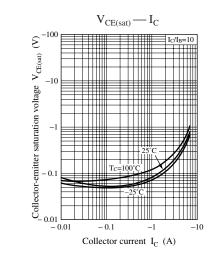
Rank	R	Q	Р
$h_{\rm FE1}$	40 to 90	70 to 150	120 to 250

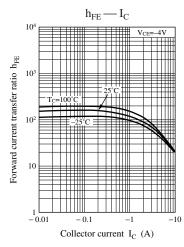
Note) The part numbers in the parenthesis show conventional part number.

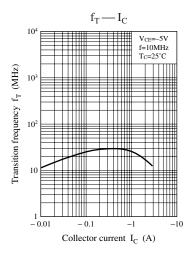


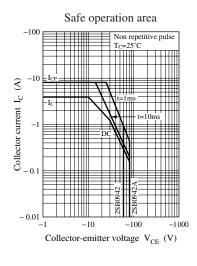


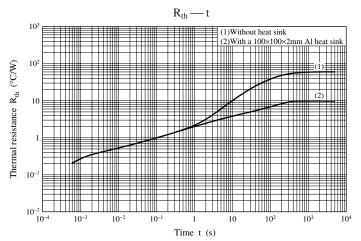












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